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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: Naotake NATORI

Appln. No.: ~~UNASSIGNED~~ 10/653,924

Filing Date: September 4, 2003

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Examiner: S. Alam | Group Art Unit: 2162

U.S. PATENT DOCUMENTS

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
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	BR	6,493,713	12/2002	Kanno, Yuji	707	6	
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							Enclosed	No	Enclose	No
	OR									
	PR									
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OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

SA	VR	Self-Organization and Associative Memory, Chap. 2, Sec. 2, "Distance Measures for Patterns", Springer-Verlag Berlin Heidelberg; T. Kohonen; 1984, pp. 59-66
SA	WR	A Method for the Correction of Garbled Words Based on the Levenshtein Metric, IEEE Transactions on Computers, Vol. C-25, No. 2; T. Okuda, et al.; Feb. 1976
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	AAR	

Examiner SAlam Date Considered: 3/31/06

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.